



# BEST PAPER AWARD

The Best Paper Award Committee of the  
*35<sup>th</sup> European Symposium on Reliability of Electron Devices,  
Failure Physics and Analysis, ESREF 2024, Parma, Italy, September 23-26*

presents the Best Paper Award to the paper entitled  
***Reading reliability in 1S1R OTS+PCM devices  
based on Double Patterned Self Aligned Structure***

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